



# Anisotropy of single-spin relaxation and spin-valley mixing in silicon quantum dots

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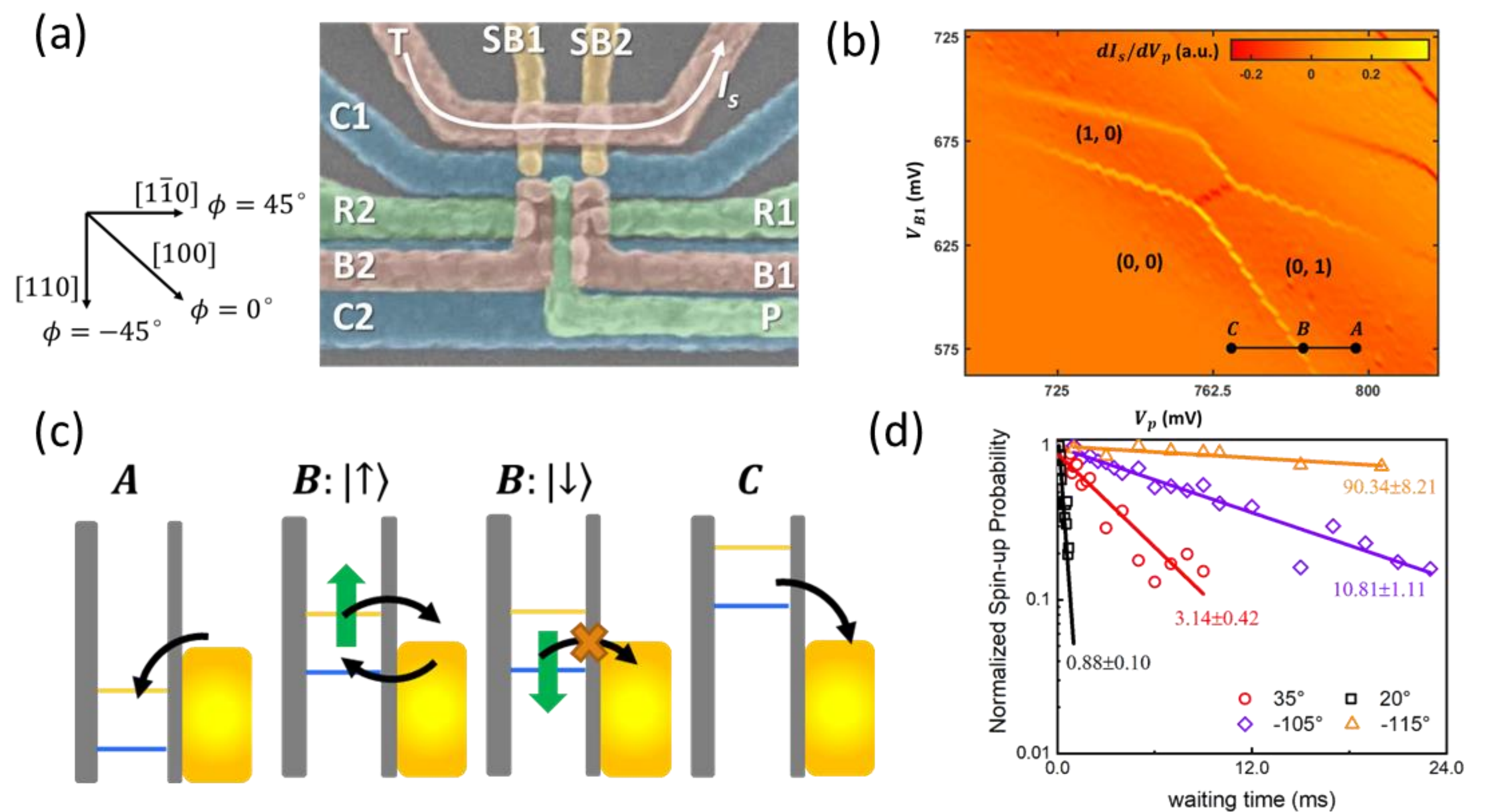
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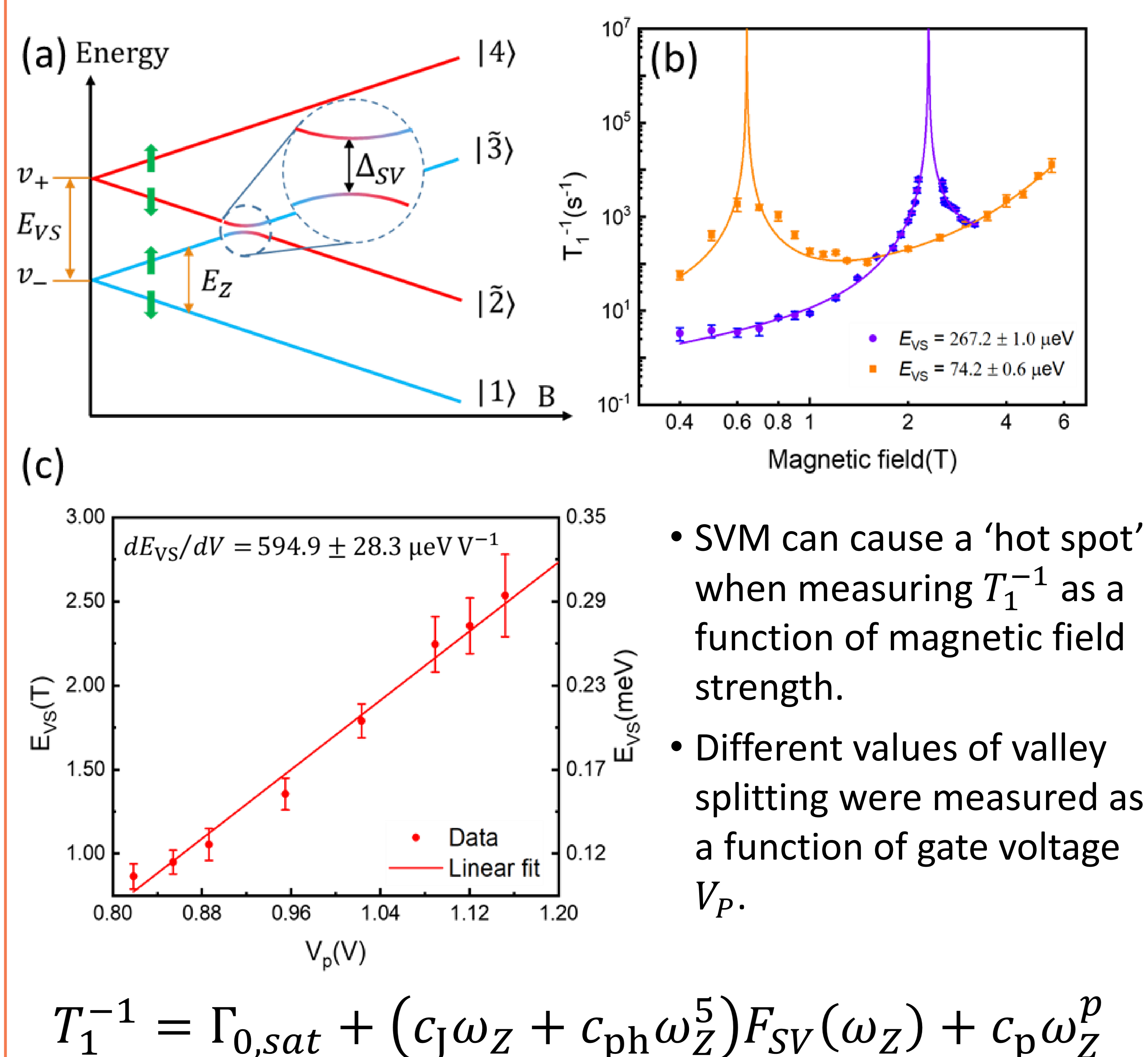
## Motivation/Objective

- Spin qubits based on silicon quantum dots (QDs) provide a promising platform for large-scale quantum computation due to the high control and readout fidelity as well as compatibility with modern semiconductor technology [1-2].
- A double quantum dot (DQD) in silicon was fabricated and a charge stability diagram was measured by charge sensing.
- Single-shot readout of single spin in silicon quantum dot and measurement of spin relaxation times [3].
- Spin-valley mixing (SVM) was characterized by measuring spin relaxation rate ( $T_1^{-1}$ ) as a function of strength and orientation of the external magnetic field [4].

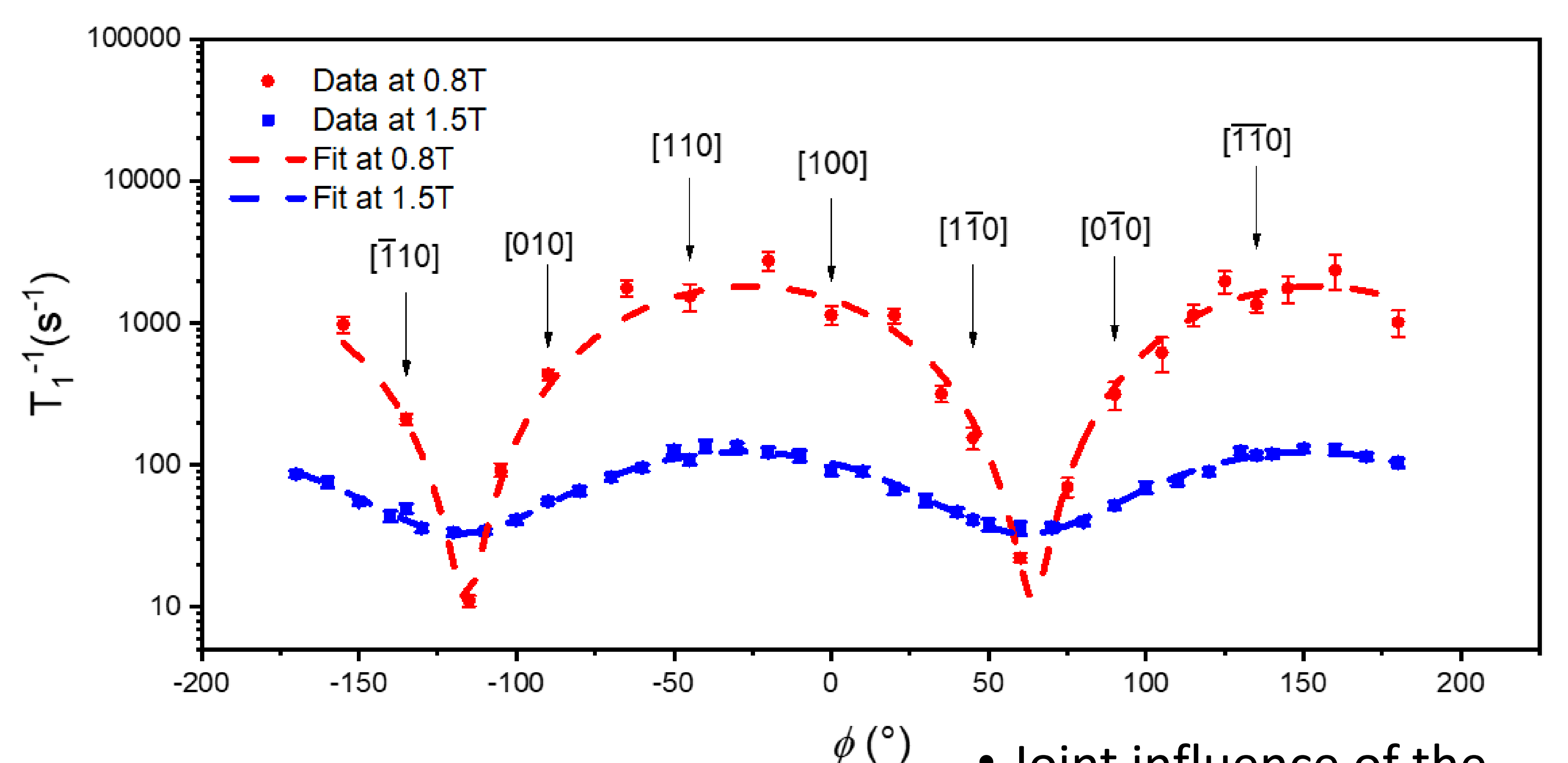
## Single-shot readout of a single spin in silicon quantum dot



## Tunable valley splitting



## Anisotropy of spin-valley relaxation rate



$$T_1^{-1} = \Gamma_{SV}(\phi) + \Gamma_0$$

$$\Gamma_{SV}(\phi) = A[\sin \phi - (\alpha_+/\alpha_-) \cos \phi]^2$$

B	0.8 T	1.5 T
$\alpha_D/\alpha_R$	2.9033	3.302
$\Gamma_0$ (Hz)	11.4136	32.79108

- Joint influence of the Rashba term ( $\alpha_R$ ) and Dresselhaus term ( $\alpha_D$ ) of SVM causes a sinusoidal variation of  $T_1^{-1}$  as a function of rotation angle of in-plane magnetic field.
- From the position of the minimal  $T_1^{-1}$  the ratio of  $\alpha_D$  and  $\alpha_R$  can be inferred.

## Future Directions

- Coherent control of single spin using electron spin resonance (ESR).
- Fidelity characterization of single-spin qubit.
- Implementation of single- and two- qubit logic gates.

## References

- [1] C. H. Yang, K. W. Chan and R. Harper *et al.*, Nat. Electron. **2**, 151-158 (2019).
- [2] W. Huang, C.H. Yang, and K. W. Chan *et al.*, Nature. **569**, 532-536 (2019).
- [3] C. H. Yang, A. Rossi, R. Ruskov and *et al.*, Nat. Commun. **4**: 2069 (2013).
- [4] P. Huang, X. Hu., Phys. Rev. B. **90**, 235315 (2014).